

# Intelligent Power Module and Gate Drive Interface Optocouplers

## Technical Data

**HCPL-4506**  
**HCPL-J456**  
**HCPL-0466**  
**HCNW4506**

### Features

- **Performance Specified for Common IPM Applications over Industrial Temperature Range: -40°C to 100°C**
- **Fast Maximum Propagation Delays**  
 $t_{PHL} = 480 \text{ ns}$   
 $t_{PLH} = 550 \text{ ns}$
- **Minimized Pulse Width Distortion**  
**PWD = 450 ns**
- **15 kV/ $\mu\text{s}$  Minimum Common Mode Transient Immunity at  $V_{CM} = 1500 \text{ V}$**
- **CTR > 44% at  $I_F = 10 \text{ mA}$**
- **Safety Approval UL Recognized**  
 -2500 V rms / 1 min. for HCPL-4506/0466  
 -3750 V rms / 1 min. for HCPL-J456  
 -5000 V rms / 1 min. for HCPL-4506 Option 020 and HCNW4506

### CSA Approved

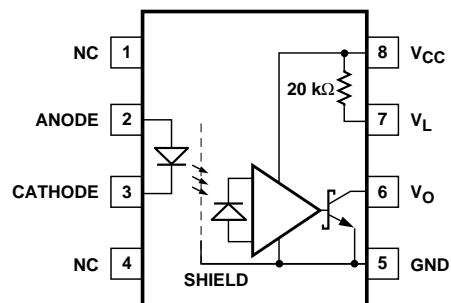
### VDE0884 Approved

- $V_{IORM} = 560 \text{ Vpeak}$  for HCPL-0466 Option 060
- $V_{IORM} = 630 \text{ Vpeak}$  for HCPL-4506 Option 060
- $V_{IORM} = 891 \text{ Vpeak}$  for HCPL-J456
- $V_{IORM} = 1414 \text{ Vpeak}$  for HCNW4506

### Applications

- **IPM Isolation**
- **Isolated IGBT/MOSFET Gate Drive**
- **AC and Brushless DC Motor Drives**
- **Industrial Inverters**

### Functional Diagram



### Truth Table

LED	$V_O$
ON	L
OFF	H

The connection of a 0.1  $\mu\text{F}$  bypass capacitor between pins 5 and 8 is recommended.

**CAUTION:** It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD.

## Description

The HCPL-4506 and HCPL-0466 contain a GaAsP LED while the HCPL-J456 and the HCNW4506 contain an AlGaAs LED. The LED is optically coupled to an integrated high gain photo detector. Minimized propagation delay

difference between devices makes these optocouplers excellent solutions for improving inverter efficiency through reduced switching dead time.

An on chip 20 k $\Omega$  output pull-up resistor can be enabled by

shorting output pins 6 and 7, thus eliminating the need for an external pull-up resistor in common IPM applications. Specifications and performance plots are given for typical IPM applications.

## Selection Guide

Package Type	Standard 8-Pin DIP (300 Mil)	White Mold 8-Pin DIP (300 Mil)	Small Outline SO8	Widebody (400 Mil)	Hermetic*
Part Number	HCPL-4506	HCPL-J456	HCPL-0466	HCNW4506	HCPL-5300 HCPL-5301
VDE0884 Approval	V <sub>IORM</sub> = 630 V <sub>peak</sub> (Option 060)	V <sub>IORM</sub> = 891 V <sub>peak</sub>	V <sub>IORM</sub> = 560 V <sub>peak</sub> (Option 060)	V <sub>IORM</sub> = 1414 V <sub>peak</sub>	—

\*Technical data for these products are on separate Agilent publications.

## Ordering Information

Specify Part Number followed by Option Number (if desired).

Example:

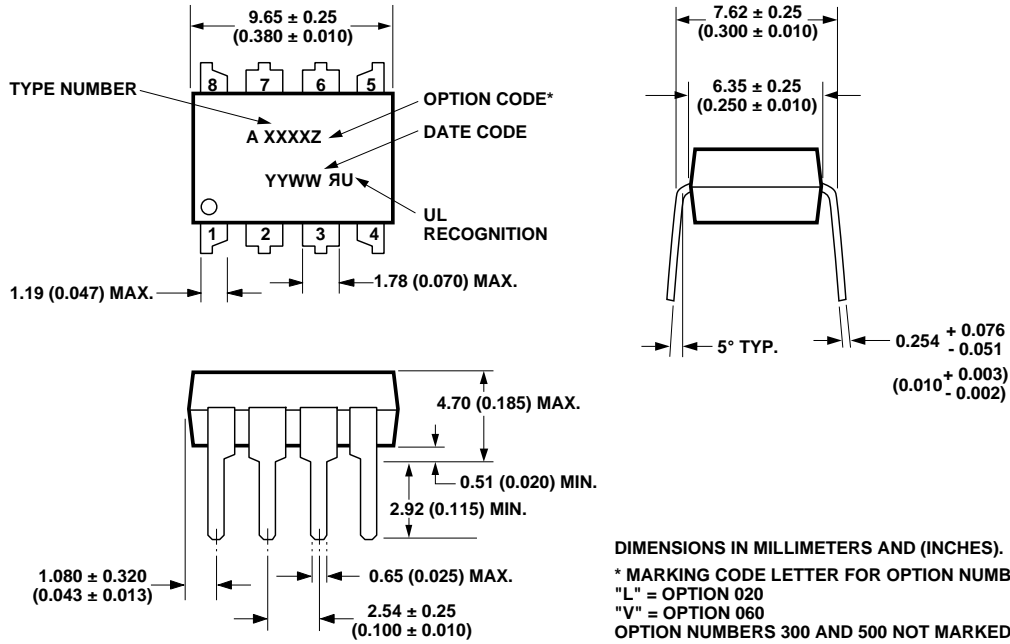
HCPL-4506#XXX

- 020 = UL 5000 V rms/1 minute Option\*\* for HCPL-4506 Only.
- 060 = VDE0884 Option\*\* for HCPL-4506/0466.
- 300 = Gull Wing Lead Option for HCPL-4506/J456, HCNW4506.
- 500 = Tape and Reel Packaging Option

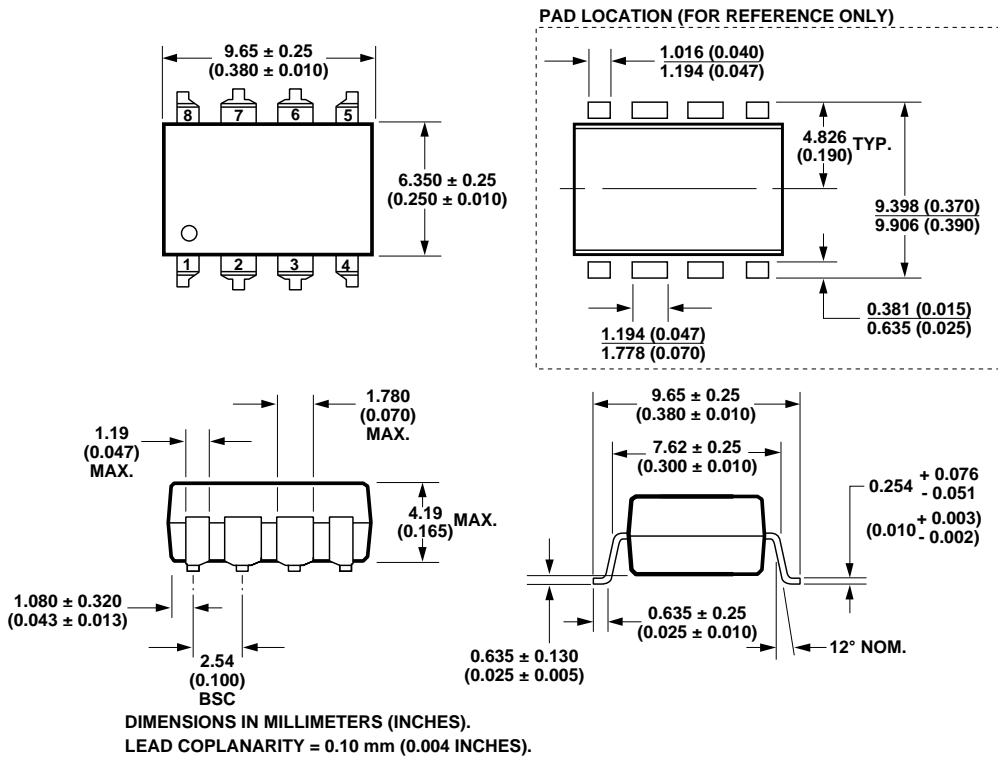
Option data sheets are available. Contact Agilent sales representative or authorized distributor for information.

\*\*Combination of Option 020 and Option 060 is not available.

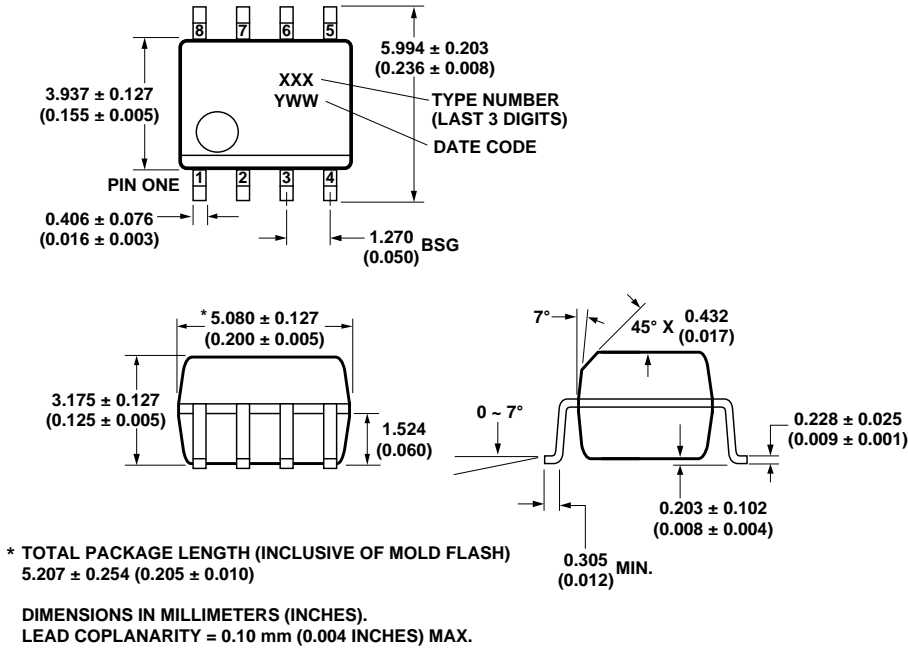
### Package Outline Drawings HCPL-4506 and HCPL-J456 Outline Drawing



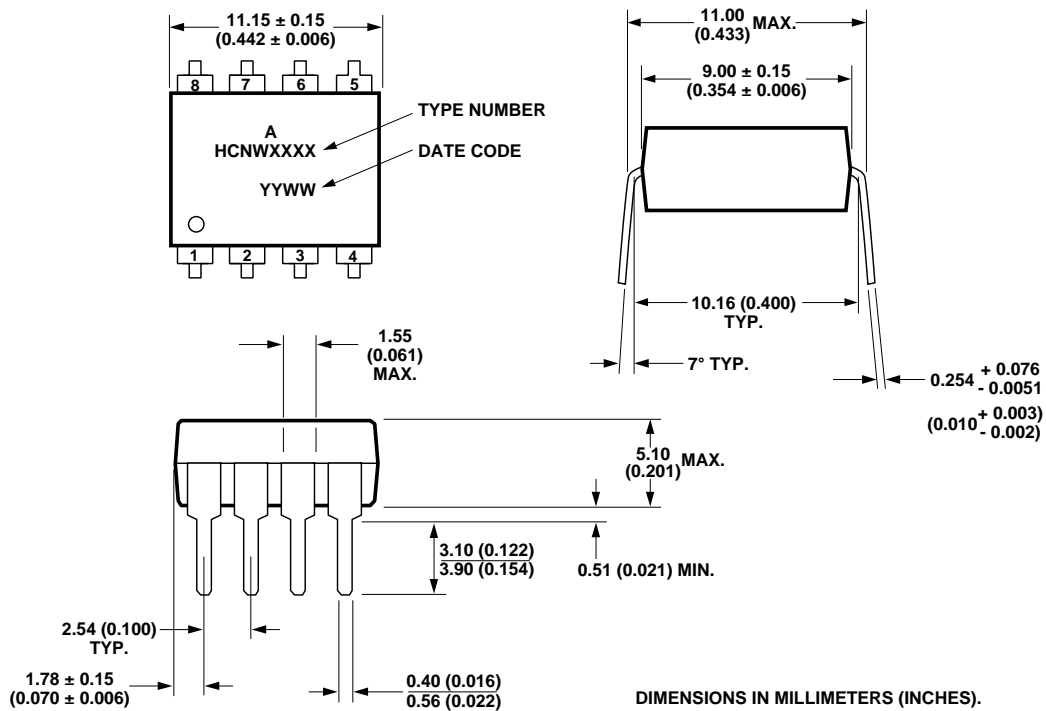
### HCPL-4506 and HCPL-J456 Gull Wing Surface Mount Option 300 Outline Drawing



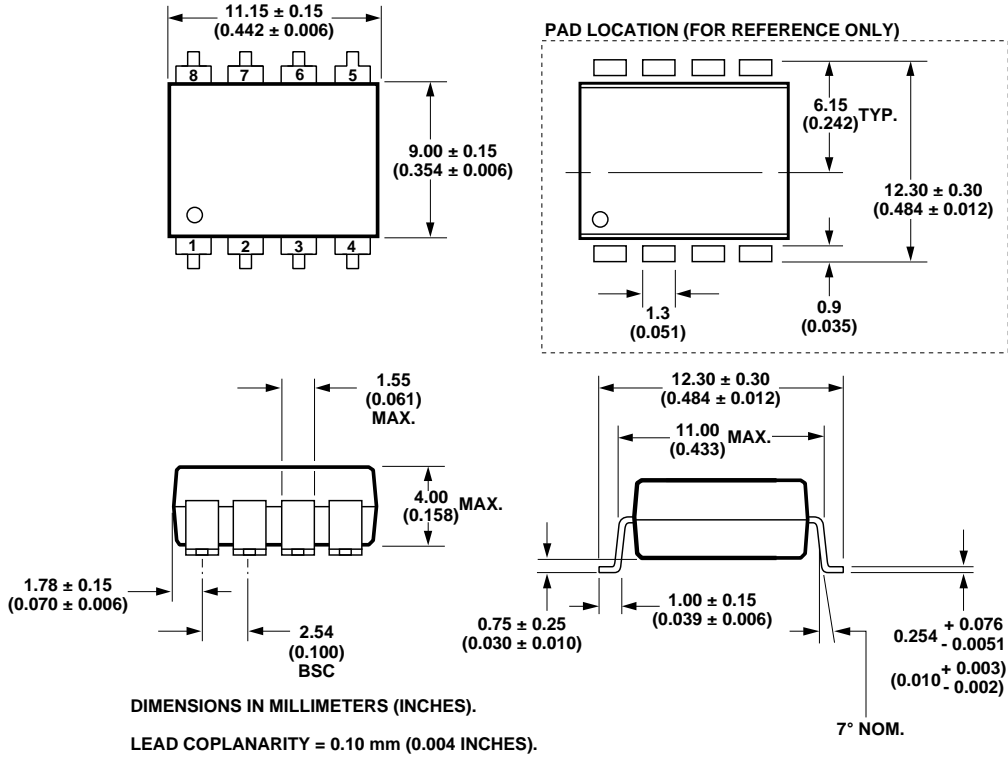
### HCPL-0466 Outline Drawing (8-Pin Small Outline Package)



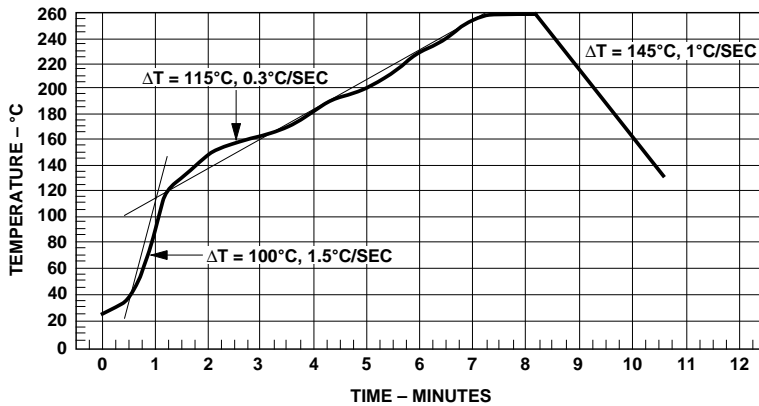
### HCNW4506 Outline Drawing (8-Pin Widebody Package)



### HCNW4506 Gull Wing Surface Mount Option 300 Outline Drawing



### Solder Reflow Temperature Profile



Note: Use of nonchlorine activated fluxes is recommended.

## Regulatory Information

The devices contained in this data sheet have been approved by the following agencies:

Agency/Standard	HCPL-4506	HCPL-J456	HCPL-0466	HCNW4506
Underwriters Laboratories (UL) UL 1577 Recognized under UL 1577, Component Recognized Program, Category FPQU2, File E55361	✓	✓	✓	✓
Canadian Standards Association (CSA) File CA88324	✓	✓	✓	✓
Component Acceptance Notice #5				
Verband Deutscher Elektrotechniker (VDE) DIN VDE 0884 (June 1992)	✓	✓		✓
Technischer Überwachungs-Verein Rheinland (TUV) Certificate R9650938			✓	

## Insulation and Safety Related Specifications

Parameter	Symbol	Value				Units	Conditions
		HCPL-4506	HCPL-J456	HCPL-0466	HCNW4506		
Minimum External Air Gap (External Clearance)	L(101)	7.1	7.4	4.9	9.6	mm	Measured from input terminals to output terminals, shortest distance through air.
Minimum External Tracking (External Creepage)	L(102)	7.4	8.0	4.8	10.0	mm	Measured from input terminals to output terminals, shortest distance path along body.
Minimum Internal Plastic Gap (Internal Clearance)		0.08	0.5	0.08	1.0	mm	Through insulation distance, conductor to conductor, usually the direct distance between the photoemitter and photodetector inside the optocoupler cavity.
Minimum Internal Tracking (Internal Creepage)		NA	NA	NA	4.0	mm	Measured from input terminals to output terminals, along internal cavity.
Tracking Resistance (Comparative Tracing Index)	CTI	≥ 175	≥ 175	≥ 175	≥ 200	Volts	DIN IEC 112/VDE 0303 Part 1
Isolation Group		IIIa	IIIa	IIIa	IIIa		Material Group (DIN VDE 0110, 1/89, Table 1)

All Agilent data sheets report the creepage and clearance inherent to the optocoupler component itself. These dimensions are needed as a starting point for the equipment designer when determining the circuit insulation requirements. However, once mounted on a printed circuit board, minimum creepage and clearance requirements must be met as specified for individual equipment standards. For creepage, the shortest distance path along the surface of a printed circuit board between the solder fillets of the input and output leads must be considered. There are recommended techniques such as grooves and ribs which may be used on a printed circuit board to achieve desired creepage and clearances. Creepage and clearance distances will also change depending on factors such as pollution degree and insulation level.

### VDE 0884 Insulation Related Characteristics

Description	Symbol	HCPL-0466 Option 060	HCPL-4506 Option 060	HCPL-J456	HCNW4506	Unit
Installation classification per DIN VDE 0110/1.89, Table 1 for rated mains voltage $\leq 150$ V rms for rated mains voltage $\leq 300$ V rms for rated mains voltage $\leq 450$ V rms for rated mains voltage $\leq 600$ V rms for rated mains voltage $\leq 1000$ V rms		I-IV I-III	I-IV I-IV I-III	I-IV I-IV I-III	I-IV I-IV I-IV I-III	
Climatic Classification		55/100/21	55/100/21	55/100/21	55/100/21	
Pollution Degree (DIN VDE 0110/1.89)		2	2	2	2	
Maximum Working Insulation Voltage	$V_{IORM}$	560	630	891	1414	$V_{peak}$
Input to Output Test Voltage, Method b* $V_{IORM} \times 1.875 = V_{PR}$ , 100% Production Test with $t_m =$ 1 sec, Partial Discharge $< 5pC$	$V_{PR}$	1050	1181	1670	2652	$V_{peak}$
Input to Output Test Voltage, Method a* $V_{IORM} \times 1.5 = V_{PR}$ , Type and Sample Test, $t_m = 60$ sec, Partial Discharge $< 5pC$	$V_{PR}$	840	945	1336	2121	$V_{peak}$
Highest Allowable Overvoltage* (Transient Overvoltage, $t_{ini} = 10$ sec)	$V_{IOTM}$	4000	6000	6000	8000	$V_{peak}$
Safety Limiting Values – maximum values allowed in the event of a fail- ure, also see Thermal Derating curve.						
Case Temperature	$T_S$	150	175	175	150	$^{\circ}C$
Input Current	$I_{S INPUT}$	150	230	400	400	mA
Output Power	$P_{S OUTPUT}$	600	600	600	700	mW
Insulation Resistance at $T_S$ , $V_{IO} = 500$ V	$R_S$	$\geq 10^9$	$\geq 10^9$	$\geq 10^9$	$\geq 10^9$	$\Omega$

\*Refer to the optocoupler section of the Designer's Catalog, under regulatory information (VDE 0884) for a detailed description of Method a and Method b partial discharge test profiles.

Note: These optocouplers are suitable for "safe electrical isolation" only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.

Note: Insulation Characteristics are per DIN VDE 0884 (June 1992 revision).

Note: Surface mount classification is Class A in accordance with CECC 00802.

## Absolute Maximum Ratings

Parameter	Symbol	Min.	Max.	Units
Storage Temperature	$T_S$	-55	125	°C
Operating Temperature	$T_A$	-40	100	°C
Average Input Current <sup>[1]</sup>	$I_{F(avg)}$		25	mA
Peak Input Current <sup>[2]</sup> (50% duty cycle, $\leq 1$ ms pulse width)	$I_{F(peak)}$		50	mA
Peak Transient Input Current (<1 $\mu$ s pulse width, 300 pps)	$I_{F(tran)}$		1.0	A
Reverse Input Voltage (Pin 3-2)	HCPL-4506, HCPL-0466	$V_R$	5	Volts
	HCPL-J456, HCNW4506		3	
Average Output Current (Pin 6)	$I_{O(avg)}$		15	mA
Resistor Voltage (Pin 7)	$V_7$	-0.5	$V_{CC}$	Volts
Output Voltage (Pin 6-5)	$V_O$	-0.5	30	Volts
Supply Voltage (Pin 8-5)	$V_{CC}$	-0.5	30	Volts
Output Power Dissipation <sup>[3]</sup>	$P_O$		100	mW
Total Power Dissipation <sup>[4]</sup>	$P_T$		145	mW
Lead Solder Temperature (HCPL-4506, HCPL-J456)	260°C for 10 s, 1.6 mm below seating plane			
Lead Solder Temperature (HCNW4506)	260°C for 10 s (up to seating plane)			
Infrared and Vapor Phase Reflow Temperature (HCPL-0466 and Option 300)	See <b>Package Outline Drawings</b> Section			

## Recommended Operating Conditions

Parameter	Symbol	Min.	Max.	Units
Power Supply Voltage	$V_{CC}$	4.5	30	Volts
Output Voltage	$V_O$	0	30	Volts
Input Current (ON)	$I_{F(on)}$	10	20	mA
Input Voltage (OFF)	$V_{F(off)}$ *	-5	0.8	V
Operating Temperature	$T_A$	-40	100	°C

\*Recommended  $V_{F(OFF)}$  = -3 V to 0.8 V for HCPL-J456, HCNW4506.



## Electrical Specifications

Over recommended operating conditions unless otherwise specified:

$T_A = -40^\circ\text{C}$  to  $+100^\circ\text{C}$ ,  $V_{CC} = +4.5\text{ V}$  to  $30\text{ V}$ ,  $I_{F(\text{on})} = 10\text{ mA}$  to  $20\text{ mA}$ ,  $V_{F(\text{off})} = -5\text{ V}$  to  $0.8\text{ V}^\dagger$

Parameter	Symbol	Device	Min.	Typ.*	Max.	Units	Test Conditions	Fig.	Note
Current Transfer Ratio	CTR		44	90		%	$I_F = 10\text{ mA}$ , $V_O = 0.6\text{ V}$		5
Low Level Output Current	$I_{OL}$		4.4	9.0		mA	$I_F = 10\text{ mA}$ , $V_O = 0.6\text{ V}$	1, 2	
Low Level Output Voltage	$V_{OL}$			0.3	0.6	V	$I_O = 2.4\text{ mA}$		
Input Threshold Current	$I_{TH}$	HCPL-4506 HCPL-0466 HCNW4506		1.5	5	mA	$V_O = 0.8\text{ V}$ , $I_O = 0.75\text{ mA}$	1	16
		HCPL-J456		0.6					
High Level Output Current	$I_{OH}$			5	50	$\mu\text{A}$	$V_F = 0.8\text{ V}$	3	
High Level Supply Current	$I_{CCH}$			0.6	1.3	mA	$V_F = 0.8\text{ V}$ , $V_O = \text{Open}$		16
Low Level Supply Current	$I_{CCL}$			0.6	1.3	mA	$I_F = 10\text{ mA}$ , $V_O = \text{Open}$		16
Input Forward Voltage	$V_F$	HCPL-4506 HCPL-0466		1.5	1.8	V	$I_F = 10\text{ mA}$	4	
		HCPL-J456	1.2	1.6	1.95	5			
		HCNW4506		1.6	1.85				
Temperature Coefficient of Forward Voltage	$\Delta V_F/\Delta T_A$	HCPL-4506 HCPL-0466		-1.6		mV/°C	$I_F = 10\text{ mA}$		
		HCPL-J456 HCNW4506		-1.3					
Input Reverse Breakdown Voltage	$BV_R$	HCPL-4506 HCPL-0466	5			V	$I_R = 10\text{ }\mu\text{A}$		
		HCPL-J456 HCNW4506	3				$I_R = 100\text{ }\mu\text{A}$		
Input Capacitance	$C_{IN}$	HCPL-4506 HCPL-0466		60		pF	$f = 1\text{ MHz}$ , $V_F = 0\text{ V}$		
		HCPL-J456 HCNW4506		72					
Internal Pull-up Resistor	$R_L$		14	20	25	k $\Omega$	$T_A = 25^\circ\text{C}$		12, 13
Internal Pull-up Resistor Temperature Coefficient	$\Delta R_L/\Delta T_A$			0.014		k $\Omega$ /°C			

\*All typical values at  $25^\circ\text{C}$ ,  $V_{CC} = 15\text{ V}$ .

$^\dagger V_{F(\text{off})} = -3\text{ V}$  to  $0.8\text{ V}$  for HCPL-J456, HCNW4506.

### Switching Specifications ( $R_L = 20\text{ k}\Omega$ External)

Over recommended operating conditions unless otherwise specified:

$T_A = -40^\circ\text{C}$  to  $+100^\circ\text{C}$ ,  $V_{CC} = +4.5\text{ V}$  to  $30\text{ V}$ ,  $I_{F(\text{on})} = 10\text{ mA}$  to  $20\text{ mA}$ ,  $V_{F(\text{off})} = -5\text{ V}$  to  $0.8\text{ V}^\dagger$

Parameter	Symbol	Min.	Typ.*	Max.	Units	Test Conditions	Fig.	Note
Propagation Delay Time to Logic Low at Output	$T_{\text{PHL}}$	30	200	400	ns	$C_L = 100\text{ pF}$ $I_{F(\text{on})} = 10\text{ mA}$ , $V_{F(\text{off})} = 0.8\text{ V}$ , $V_{CC} = 15.0\text{ V}$ ,	6, 8, 10- 13	11, 14, 16
			100	480				
Propagation Delay Time to High Output Level	$T_{\text{PLH}}$	270	400	550	ns	$C_L = 100\text{ pF}$ $V_{\text{THLH}} = 2.0\text{ V}$ , $V_{\text{THHL}} = 1.5\text{ V}$		
			130					
Pulse Width Distortion	PWD		200	450	ns	$C_L = 100\text{ pF}$		20
Propagation Delay Difference Between Any 2 Parts	$t_{\text{PLH}} - t_{\text{PHL}}$	-150	200	450	ns			17
Output High Level Common Mode Transient Immunity	$ CM_H $	15	30		kV/ $\mu\text{s}$	$I_F = 0\text{ mA}$ , $V_O > 3.0\text{ V}$	7	18
Output Low Level Common Mode Transient Immunity	$ CM_L $	15	30		kV/ $\mu\text{s}$	$I_F = 10\text{ mA}$ , $V_O < 1.0\text{ V}$		19

### Switching Specifications ( $R_L = \text{Internal Pull-up}$ )

Over recommended operating conditions unless otherwise specified:

$T_A = -40^\circ\text{C}$  to  $+100^\circ\text{C}$ ,  $V_{CC} = +4.5\text{ V}$  to  $30\text{ V}$ ,  $I_{F(\text{on})} = 10\text{ mA}$  to  $20\text{ mA}$ ,  $V_{F(\text{off})} = -5\text{ V}$  to  $0.8\text{ V}^\dagger$

Parameter	Symbol	Min.	Typ.*	Max.	Units	Test Conditions	Fig.	Note
Propagation Delay Time to Logic Low at Output	$t_{\text{PHL}}$	20	200	400	ns	$I_{F(\text{on})} = 10\text{ mA}$ , $V_{F(\text{off})} = 0.8\text{ V}$ , $V_{CC} = 15.0\text{ V}$ , $C_L = 100\text{ pF}$ , $V_{\text{THLH}} = 2.0\text{ V}$ , $V_{\text{THHL}} = 1.5\text{ V}$	6, 9	11-14, 16
			485					
Propagation Delay Time to High Output Level	$t_{\text{PLH}}$	220	450	650	ns			
Pulse Width Distortion	PWD		250	500	ns			20
Propagation Delay Difference Between Any 2 Parts	$t_{\text{PLH}} - t_{\text{PHL}}$	-150	250	500	ns			17
Output High Level Common Mode Transient Immunity	$ CM_H $		30		kV/ $\mu\text{s}$	$I_F = 0\text{ mA}$ , $V_O > 3.0\text{ V}$	7	18
Output Low Level Common Mode Transient Immunity	$ CM_L $		30		kV/ $\mu\text{s}$	$I_F = 16\text{ mA}$ , $V_O < 1.0\text{ V}$		19
Power Supply Rejection	PSR		1.0		$V_{\text{p-p}}$	Square Wave, $t_{\text{RISE}}$ , $t_{\text{FALL}}$ > 5 ns, no bypass capacitors		16

\*All typical values at  $25^\circ\text{C}$ ,  $V_{CC} = 15\text{ V}$ .

$^\dagger V_{F(\text{off})} = -3\text{ V}$  to  $0.8\text{ V}$  for HCPL-J456, HCNW4506.

## Package Characteristics

Over recommended temperature ( $T_A = -40^\circ\text{C}$  to  $100^\circ\text{C}$ ) unless otherwise specified.

Parameter	Sym.	Device	Min.	Typ.*	Max.	Units	Test Conditions	Fig.	Note
Input-Output Momentary Withstand Voltage†	$V_{\text{ISO}}$	HCPL-4506	2500			V rms	RH < 50% t = 1 min. $T_A = 25^\circ\text{C}$		6,7,10
		HCPL-0466							
		HCPL-J456	3750						6,8,10
		HCPL-4506 Option020	5000						6,9, 15
		HCNW4506	5000						6,9,10
Resistance (Input-Output)	$R_{\text{I-O}}$	HCPL-4506		$10^{12}$		$\Omega$	$V_{\text{I-O}} = 500 \text{ Vdc}$		6
		HCPL-J456							
		HCPL-0466							
		HCNW4506	$10^{12}$	$10^{13}$					
Capacitance (Input-Output)	$C_{\text{I-O}}$	HCPL-4506		0.6		pF	f = 1 MHz		6
		HCPL-0466							
		HCPL-J456		0.8					
		HCNW4506		0.5					

\*All typical values at  $25^\circ\text{C}$ ,  $V_{\text{CC}} = 15 \text{ V}$ .

†The Input-Output Momentary Withstand Voltage is a dielectric voltage rating that should not be interpreted as an input-output continuous voltage rating. For the continuous voltage rating refer to the VDE 0884 Insulation Related Characteristics Table (if applicable), your equipment level safety specification or Agilent Application Note 1074 entitled "Optocoupler Input-Output Endurance Voltage," publication number 5963-2203E.

### Notes:

- Derate linearly above  $90^\circ\text{C}$  free-air temperature at a rate of  $0.8 \text{ mA}/^\circ\text{C}$ .
- Derate linearly above  $90^\circ\text{C}$  free-air temperature at a rate of  $1.6 \text{ mA}/^\circ\text{C}$ .
- Derate linearly above  $90^\circ\text{C}$  free-air temperature at a rate of  $3.0 \text{ mW}/^\circ\text{C}$ .
- Derate linearly above  $90^\circ\text{C}$  free-air temperature at a rate of  $4.2 \text{ mW}/^\circ\text{C}$ .
- CURRENT TRANSFER RATIO in percent is defined as the ratio of output collector current ( $I_{\text{O}}$ ) to the forward LED input current ( $I_{\text{F}}$ ) times 100.
- Device considered a two-terminal device: Pins 1, 2, 3, and 4 shorted together and Pins 5, 6, 7, and 8 shorted together.
- In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage  $\geq 3000 \text{ V rms}$  for 1 second (leakage detection current limit,  $I_{\text{I-O}} \leq 5 \mu\text{A}$ ).
- In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage  $\geq 4500 \text{ V rms}$  for 1 second (leakage detection current limit,  $I_{\text{I-O}} \leq 5 \mu\text{A}$ ).
- In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage  $\geq 6000 \text{ V rms}$  for 1 second (leakage detection current limit,  $I_{\text{I-O}} \leq 5 \mu\text{A}$ ).
- This test is performed before the 100% Production test shown in the VDE 0884 Insulation Related Characteristics Table, if applicable.
- Pulse: f = 20 kHz, Duty Cycle = 10%.
- The internal  $20 \text{ k}\Omega$  resistor can be used by shorting pins 6 and 7 together.
- Due to tolerance of the internal resistor, and since propagation delay is dependent on the load resistor value, performance can be improved by using an external  $20 \text{ k}\Omega$  1% load resistor. For more information on how propagation delay varies with load resistance, see Figure 8.
- The  $R_{\text{L}} = 20 \text{ k}\Omega$ ,  $C_{\text{L}} = 100 \text{ pF}$  load represents a typical IPM (Intelligent Power Module) load.
- See Option 020 data sheet for more information.
- Use of a  $0.1 \mu\text{F}$  bypass capacitor connected between pins 5 and 8 can improve performance by filtering power supply line noise.
- The difference between  $t_{\text{PLH}}$  and  $t_{\text{PHL}}$  between any two devices under the same test condition. (See IPM Dead Time and Propagation Delay Specifications section.)
- Common mode transient immunity in a Logic High level is the maximum tolerable  $dV_{\text{CM}}/dt$  of the common mode pulse,  $V_{\text{CM}}$ , to assure that the output will remain in a Logic High state (i.e.,  $V_{\text{O}} > 3.0 \text{ V}$ ).
- Common mode transient immunity in a Logic Low level is the maximum tolerable  $dV_{\text{CM}}/dt$  of the common mode pulse,  $V_{\text{CM}}$ , to assure that the output will remain in a Logic Low state (i.e.,  $V_{\text{O}} < 1.0 \text{ V}$ ).
- Pulse Width Distortion (PWD) is defined as  $|t_{\text{PHL}} - t_{\text{PLH}}|$  for any given device.

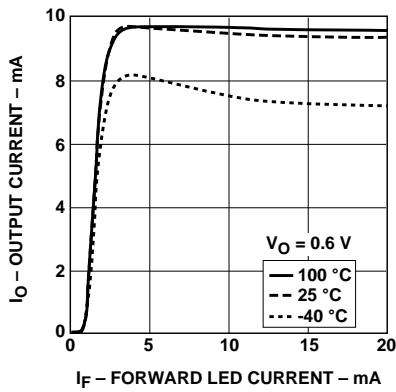


Figure 1. Typical Transfer Characteristics.

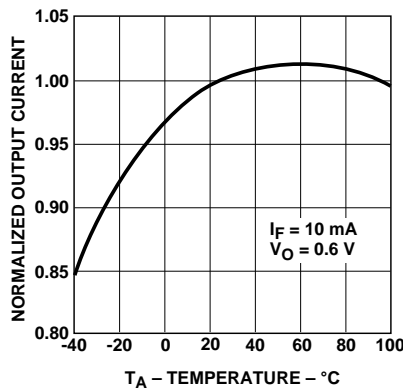


Figure 2. Normalized Output Current vs. Temperature.

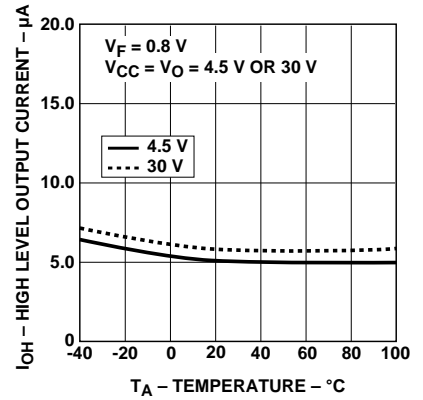


Figure 3. High Level Output Current vs. Temperature.

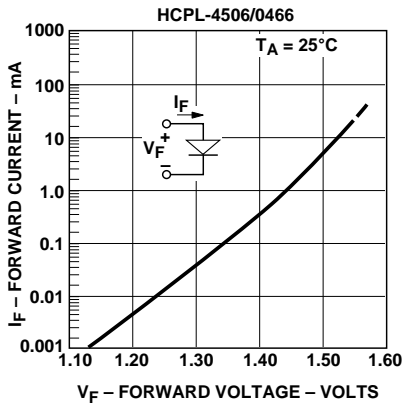


Figure 4. HCPL-4506 and HCPL-0466 Input Current vs. Forward Voltage.

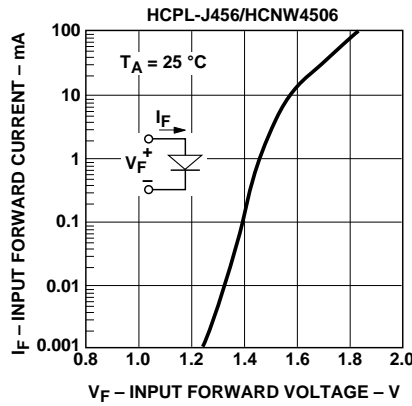


Figure 5. HCPL-J456 and HCNW4506 Input Current vs. Forward Voltage.

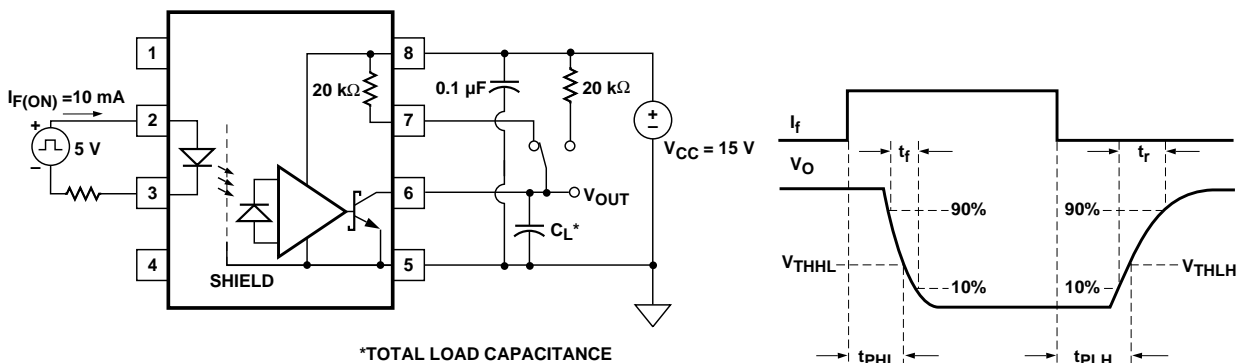


Figure 6. Propagation Delay Test Circuit.

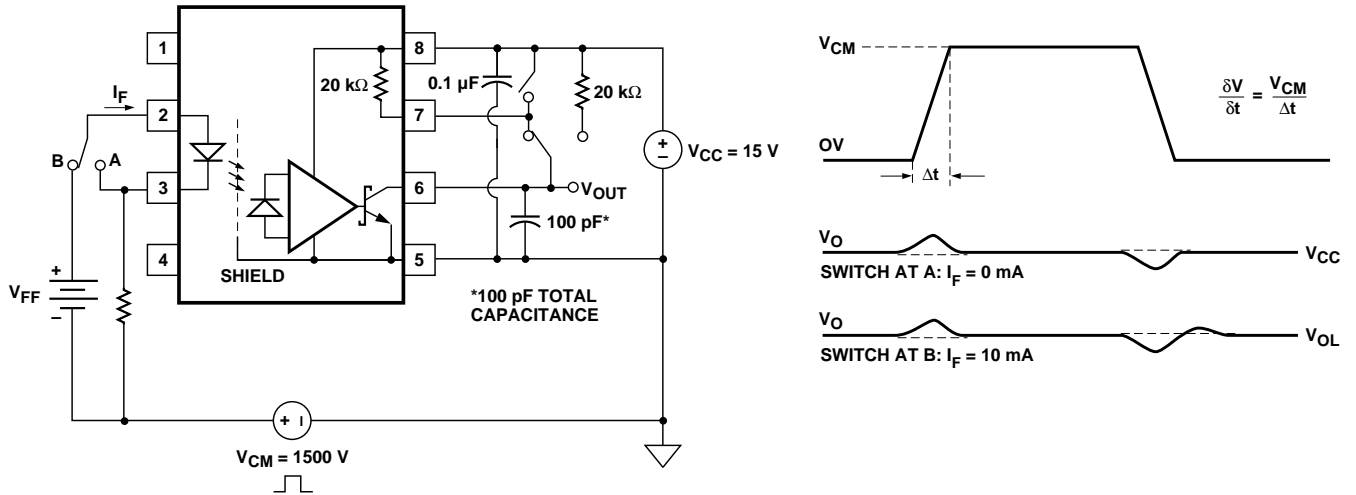


Figure 7. CMR Test Circuit. Typical CMR Waveform.

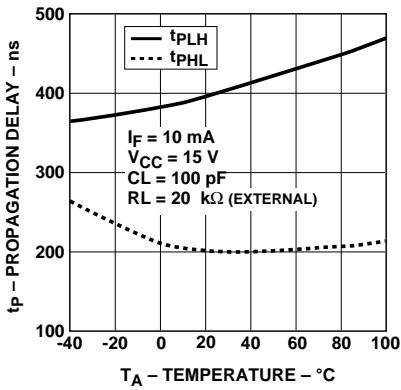


Figure 8. Propagation Delay with External 20 kΩ RL vs. Temperature.

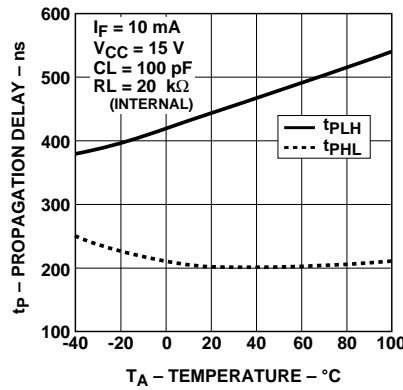


Figure 9. Propagation Delay with Internal 20 kΩ RL vs. Temperature.

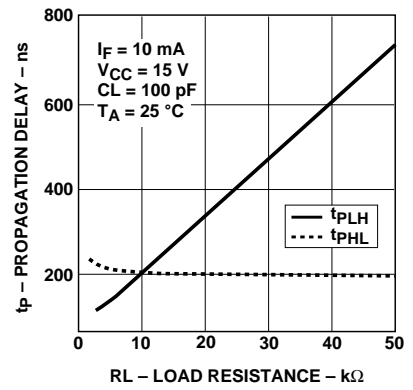


Figure 10. Propagation Delay vs. Load Resistance.

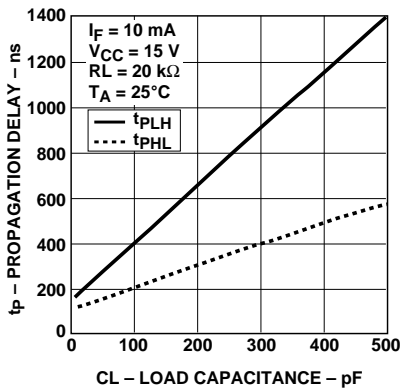


Figure 11. Propagation Delay vs. Load Capacitance.

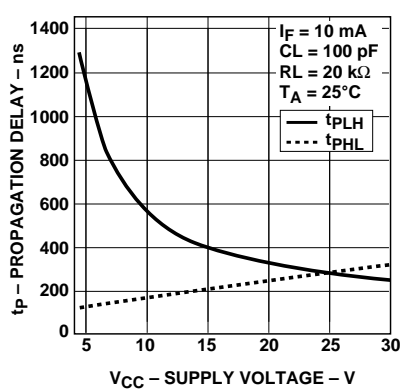


Figure 12. Propagation Delay vs. Supply Voltage.

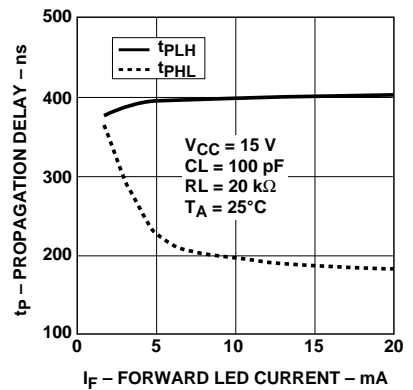


Figure 13. Propagation Delay vs. Input Current.

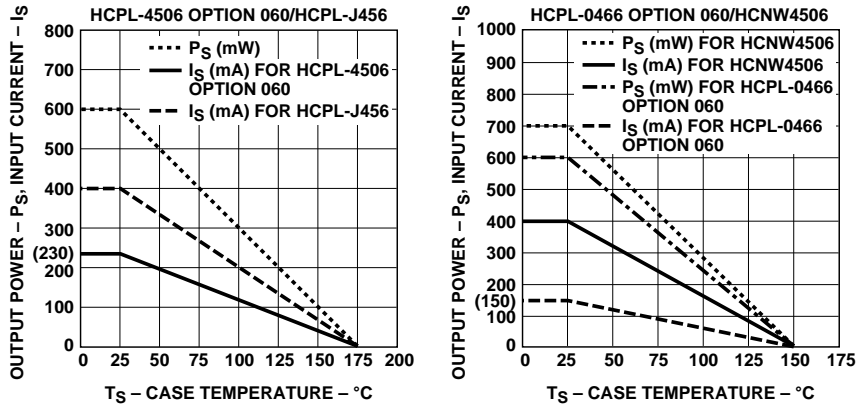


Figure 14. Thermal Derating Curve, Dependence of Safety Limiting Value with Case Temperature per VDE 0884.

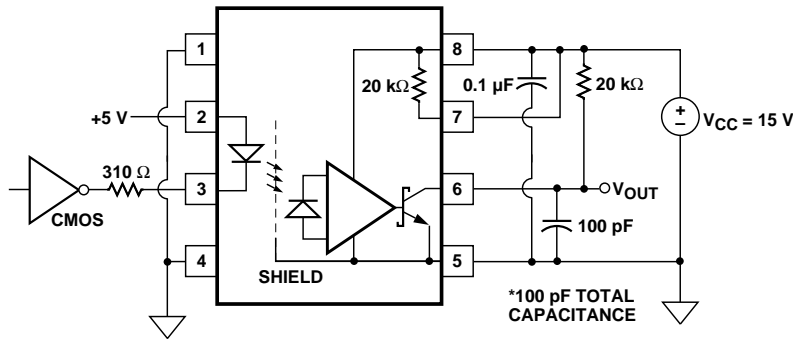


Figure 15. Recommended LED Drive Circuit.

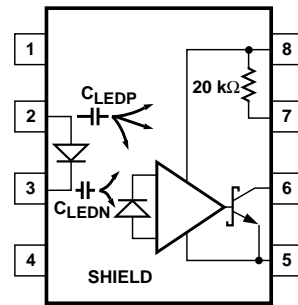


Figure 16. Optocoupler Input to Output Capacitance Model for Unshielded Optocouplers.

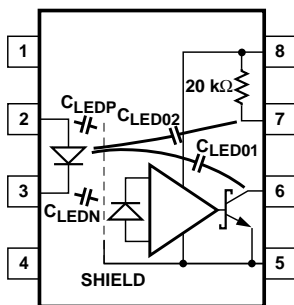


Figure 17. Optocoupler Input to Output Capacitance Model for Shielded Optocouplers.

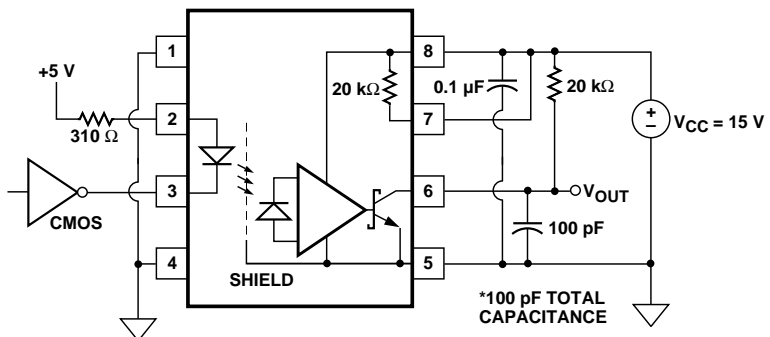


Figure 18. LED Drive Circuit with Resistor Connected to LED Anode (Not Recommended).

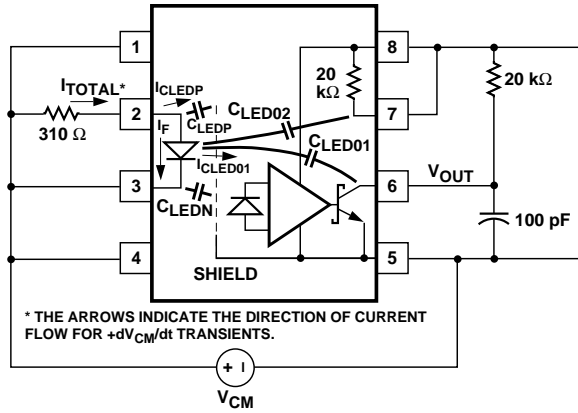


Figure 19. AC Equivalent Circuit for Figure 18 During Common Mode Transients.

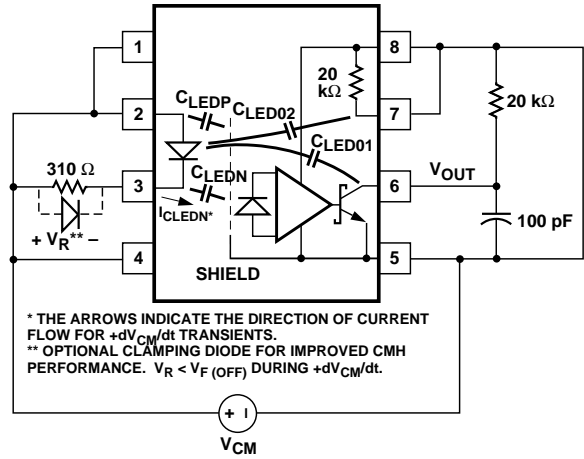


Figure 20. AC Equivalent Circuit for Figure 15 During Common Mode Transients.

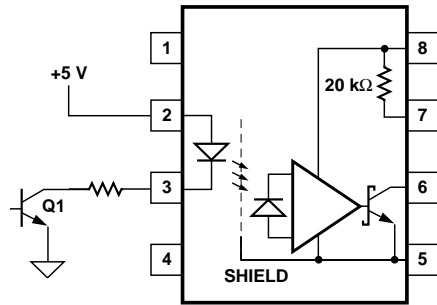


Figure 21. Not Recommended Open Collector LED Drive Circuit.

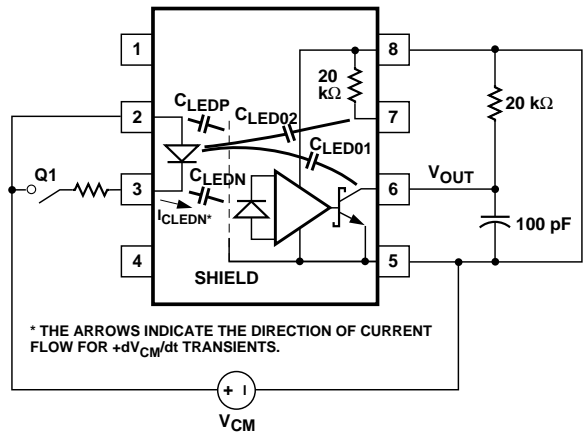


Figure 22. AC Equivalent Circuit for Figure 21 During Common Mode Transients.

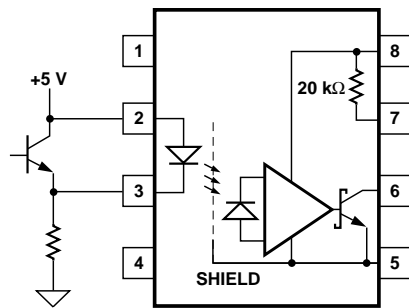


Figure 23. Recommended LED Drive Circuit for Ultra High CMR.

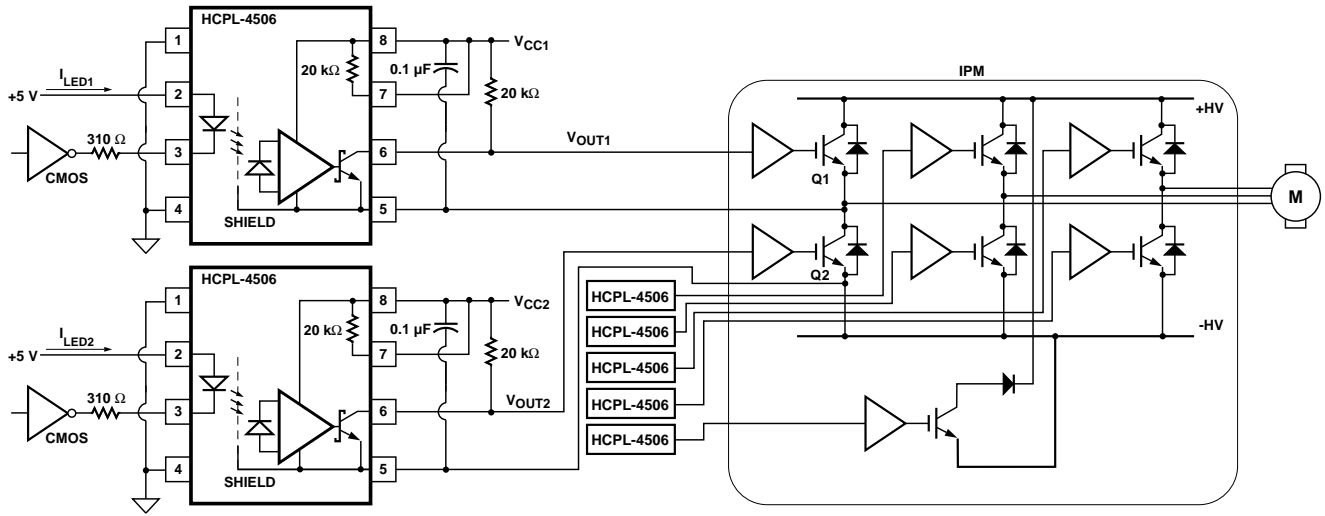
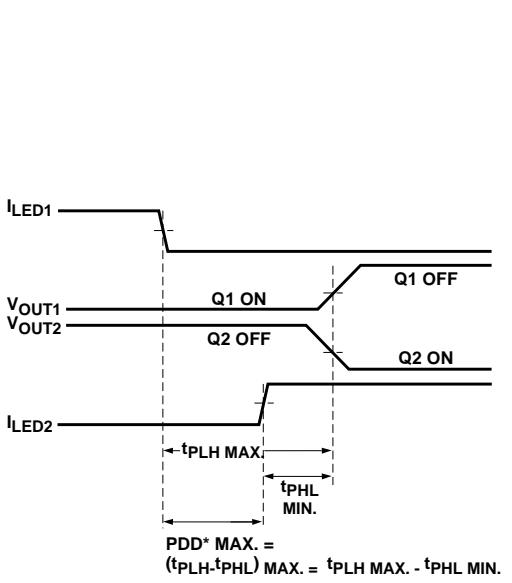


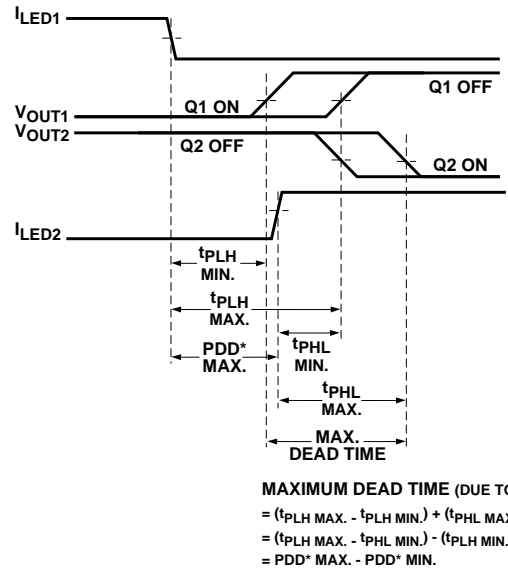
Figure 24. Typical Application Circuit.



\*PDD = PROPAGATION DELAY DIFFERENCE

NOTE: THE PROPAGATION DELAYS USED TO CALCULATE PDD ARE TAKEN AT EQUAL TEMPERATURES.

Figure 25. Minimum LED Skew for Zero Dead Time.



\*PDD = PROPAGATION DELAY DIFFERENCE

NOTE: THE PROPAGATION DELAYS USED TO CALCULATE THE MAXIMUM DEAD TIME ARE TAKEN AT EQUAL TEMPERATURES.

Figure 26. Waveforms for Dead Time Calculation.



## LED Drive Circuit Considerations for Ultra High CMR Performance

Without a detector shield, the dominant cause of optocoupler CMR failure is capacitive coupling from the input side of the optocoupler, through the package, to the detector IC as shown in Figure 16. The HCPL-4506 series improve CMR performance by using a detector IC with an optically transparent Faraday shield, which diverts the capacitively coupled current away from the sensitive IC circuitry. However, this shield does not eliminate the capacitive coupling between the LED and the optocoupler output pins and output ground as shown in Figure 17. This capacitive coupling causes perturbations in the LED current during common mode transients and becomes the major source of CMR failures for a shielded optocoupler. The main design objective of a high CMR LED drive circuit becomes keeping the LED in the proper state (on or off) during common mode transients. For example, the recommended application circuit (Figure 15), can achieve 15 kV/ $\mu$ s CMR while minimizing component complexity. Note that a CMOS gate is recommended in Figure 15 to keep the LED off when the gate is in the high state.

Another cause of CMR failure for a shielded optocoupler is direct coupling to the optocoupler output pins through  $C_{LEDO1}$  and  $C_{LEDO2}$  in Figure 17. Many factors influence the effect and magnitude of the direct coupling including: the use of an internal or external output pull-up resistor, the position of the LED current setting resistor, the

connection of the unused input package pins, and the value of the capacitor at the optocoupler output ( $C_L$ ).

Techniques to keep the LED in the proper state and minimize the effect of the direct coupling are discussed in the next two sections.

### CMR with the LED On ( $CMR_L$ )

A high CMR LED drive circuit must keep the LED on during common mode transients. This is achieved by overdriving the LED current beyond the input threshold so that it is not pulled below the threshold during a transient. The recommended minimum LED current of 10 mA provides adequate margin over the maximum  $I_{TH}$  of 5.0 mA (see Figure 1) to achieve 15 kV/ $\mu$ s CMR. Capacitive coupling is higher when the internal load resistor is used (due to  $C_{LEDO2}$ ) and an  $I_F = 16$  mA is required to obtain 10 kV/ $\mu$ s CMR.

The placement of the LED current setting resistor effects the ability of the drive circuit to keep the LED on during transients and interacts with the direct coupling to the optocoupler output. For example, the LED resistor in Figure 18 is connected to the anode. Figure 19 shows the AC equivalent circuit for Figure 18 during common mode transients. During a +dVcm/dt in Figure 19, the current available at the LED anode ( $I_{total}$ ) is limited by the series resistor. The LED current ( $I_F$ ) is reduced from its DC value by an amount equal to the current that flows through  $C_{LEDP}$  and  $C_{LEDO1}$ . The situation is made worse because the current through  $C_{LEDO1}$  has the effect of

trying to pull the output high (toward a CMR failure) at the same time the LED current is being reduced. For this reason, the recommended LED drive circuit (Figure 15) places the current setting resistor in series with the LED cathode. Figure 20 is the AC equivalent circuit for Figure 15 during common mode transients. In this case, the LED current is not reduced during a +dVcm/dt transient because the current flowing through the package capacitance is supplied by the power supply. During a -dVcm/dt transient, however, the LED current is reduced by the amount of current flowing through  $C_{LEDN}$ . But, better CMR performance is achieved since the current flowing in  $C_{LEDO1}$  during a negative transient acts to keep the output low.

Coupling to the LED and output pins is also affected by the connection of pins 1 and 4. If CMR is limited by perturbations in the LED on current, as it is for the recommended drive circuit (Figure 15), pins 1 and 4 should be connected to the input circuit common. However, if CMR performance is limited by direct coupling to the output when the LED is off, pins 1 and 4 should be left unconnected.

### CMR with the LED Off ( $CMR_H$ )

A high CMR LED drive circuit must keep the LED off ( $V_F \leq V_{F(OFF)}$ ) during common mode transients. For example, during a +dVcm/dt transient in Figure 20, the current flowing through  $C_{LEDN}$  is supplied by the parallel combination of the LED and series resistor. As long as the voltage developed across the resistor is less than  $V_{F(OFF)}$  the

LED will remain off and no common mode failure will occur. Even if the LED momentarily turns on, the 100 pF capacitor from pins 6-5 will keep the output from dipping below the threshold. The recommended LED drive circuit (Figure 15) provides about 10 V of margin between the lowest optocoupler output voltage and a 3 V IPM threshold during a 15 kV/ $\mu$ s transient with  $V_{CM} = 1500$  V. Additional margin can be obtained by adding a diode in parallel with the resistor, as shown by the dashed line connection in Figure 20, to clamp the voltage across the LED below  $V_{F(OFF)}$ .

Since the open collector drive circuit, shown in Figure 21, cannot keep the LED off during a  $+dV_{cm}/dt$  transient, it is not desirable for applications requiring ultra high  $CMR_H$  performance. Figure 22 is the AC equivalent circuit for Figure 21 during common mode transients. Essentially all the current flowing through  $C_{LEDN}$  during a  $+dV_{cm}/dt$  transient must be supplied by the LED.  $CMR_H$  failures can occur at  $dV/dt$  rates where the current through the LED and  $C_{LEDN}$  exceeds the input threshold. Figure 23 is an alternative drive circuit which does achieve ultra high  $CMR$  performance by shunting the LED in the off state.

### IPM Dead Time and Propagation Delay Specifications

The HCPL-4506 series include a Propagation Delay Difference specification intended to help designers minimize “dead time” in their power inverter designs. Dead time is the time period during which both the high and low side power transistors (Q1 and Q2 in Figure 24) are off. Any overlap in Q1 and Q2 conduction will result in large currents flowing through the power devices between the high and low voltage motor rails.

To minimize dead time the designer must consider the propagation delay characteristics of the optocoupler as well as the characteristics of the IPM IGBT gate drive circuit. Considering only the delay characteristics of the optocoupler (the characteristics of the IPM IGBT gate drive circuit can be analyzed in the same way) it is important to know the minimum and maximum turn-on ( $t_{PHL}$ ) and turn-off ( $t_{PLH}$ ) propagation delay specifications, preferably over the desired operating temperature range.

The limiting case of zero dead time occurs when the input to Q1 turns off at the same time that the input to Q2 turns on. This case determines the minimum delay between LED1 turn-off and LED2 turn-on, which is related to the worst case optocoupler propagation delay waveforms, as shown in Figure 25. A minimum dead time of zero is achieved in Figure 25 when the signal to turn on LED2

is delayed by ( $t_{PLH \max} - t_{PHL \min}$ ) from the LED1 turn off. Note that the propagation delays used to calculate PDD are taken at equal temperatures since the optocouplers under consideration are typically mounted in close proximity to each other. (Specifically,  $t_{PLH \max}$  and  $t_{PHL \min}$  in the previous equation are not the same as the  $t_{PLH \max}$  and  $t_{PHL \min}$ , over the full operating temperature range, specified in the data sheet.) This delay is the maximum value for the propagation delay difference specification which is specified at 450 ns for the HCPL-4506 series over an operating temperature range of  $-40^\circ\text{C}$  to  $100^\circ\text{C}$ .

Delaying the LED signal by the maximum propagation delay difference ensures that the minimum dead time is zero, but it does not tell a designer what the maximum dead time will be. The maximum dead time occurs in the highly unlikely case where one optocoupler with the fastest  $t_{PLH}$  and another with the slowest  $t_{PHL}$  are in the same inverter leg. The maximum dead time in this case becomes the sum of the spread in the  $t_{PLH}$  and  $t_{PHL}$  propagation delays as shown in Figure 26. The maximum dead time is also equivalent to the difference between the maximum and minimum propagation delay difference specifications. The maximum dead time (due to the optocouplers) for the HCPL-4506 series is 600 ns (=  $450 \text{ ns} - (-150 \text{ ns})$ ) over an operating temperature range of  $-40^\circ\text{C}$  to  $100^\circ\text{C}$ .



